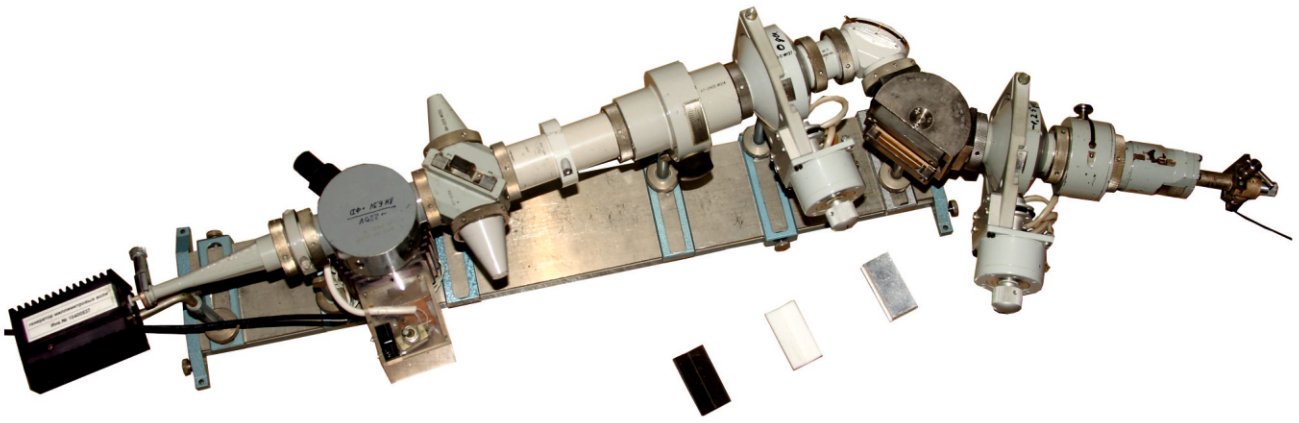
QUASIOPTICAL MULTI ANGLE TERAHERTZ ELLIPSOMETER



General View of Ellipsometer with a some testing samples

Areas of Application

Designed to research the properties of various materials by ellipsometry technique in the terahertz frequency range.

Specification

Ellipsometer has been made of elements based on hollow dielectric beamguide (diameter 20 mm). The device provides a non-destructive testing parameters of the material. The phenomenon changing the polarization of electromagnetic waves in reflection from the surface of the sample is used. Ellipsometric parameters delta and psi are measured. These parameters describe elliptical polarization of electromagnetic waves, which becomes linearly polarized electromagnetic wave after reflection at a given angle from the surface of the sample. Thickness of thin films and the refractive index measuring available using own software.

Stage of Development

IRL7, TRL8.
The manufacturing, delivering, warranty and training services are included.

Advantages

Device has no analogues in Ukraine and abroad.

IPR Protection

IPR1, IPR3

Contacts

Sergiy V. Mizrakhy; O.Ya.Usikov Institute of Radiophysics and Electronics, National Academy of Sciences of Ukraine; 380-57-7203335; smizrakhy@ire.kharkov.ua